

Notice of References Cited	Application/Control No. 10/025,584		Applicant(s)/Patent Under Reexamination KIM ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,702,207	10-1987	Hatamura et al.	123/302
	B	US-5,295,464	03-1994	Ando et al.	123/308
	C	US-5,551,392	09-1996	Yamaji et al.	123/306
	D	US-5,632,244	05-1997	Endres et al.	123/306
	E	US-6,199,534	03-2001	Tokuyasu et al.	123/301
	F	US-6,478,008	11-2002	Wolters, Peter	123/306
	G	US-6,543,410 B2	04-2003	Yoshida et al.	123/301
	H	US-6,575,133 B2	06-2003	Ries-Mueller et al.	123/306
	I	US-6,615,789 B2	09-2003	Inoue et al.	123/193.6
	J	US-6,634,333 B2	10-2003	Fujieda et al.	123/308
	K	US-6,705,280 B1	03-2004	Lippert, Eduard	123/306
	L	US-6,742,495 B2	06-2004	Ashida et al.	123/310
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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